

Notice of References Cited		Application/Control No.	Applicant(s)/Patent Under Reexamination	
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Examiner		Art Unit		Page 1 of 1
BEN C. WANG		2192		

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*	B	US-2004/0216097 A1	10-2004	Sun, Mingqiu	717/154
*	C	US-2004/0216082 A1	10-2004	Sun, Mingqiu	717/100
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NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Sherwood et al., "Automatically Characterizing Large Scale Program Behavior", 2002 ACM, pp. 45-57
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*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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